



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1602-01	DATE: 16-Mar-2016	MEANS OF DISTINGUISHING CHANGED DEVICES:
Product Affected: RFD devices (refer to attachment 2 for the affected part#)		<input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark <input type="checkbox"/> Date Code <input checked="" type="checkbox"/> Other
Date Effective: 16-Jun-2016		Traceability to the test location is maintained by IDT and available on request

Contact: IDT PCN DESK	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
E-mail: pcndesk@idt.com	Samples: Please contact your local sales representative for sample request.

DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	This notification is to advise our customers that IDT is adding Global Testing Corporation, Taiwan as an alternate facility for Test process for the selective products that are presently tested at Amkor, Korea facility. Attachment 1 details the change. Attachment 2 lists the affected parts.
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RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment 1 for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____
CUSTOMER COMMENTS: _____	

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT 1 - PCN # : TB1602-01

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding Global Testing Corporation, Taiwan as an alternate facility for Test process for the selective products that are presently tested at Amkor, Korea facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Tester configuration used at Amkor, Korea is the same as Global Testing Corporation at Taiwan. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT 1 - PCN # : TB1602-01

Qualification Information and Qualification Data: Electrical Test Correlation Results

Vehicle: F1152

Sample size: 510 electrically good units and 10 reject units

Description	Existing Test (Amkor, Korea)	Alternate Test (Global Testing Corporation, Taiwan)
Tester Platform	Catalyst	Catalyst
Loadboard	IDT board	IDT board
Test Program	F1152_FT_Rx (where x is program revision)	F1152_FT_Rx (where x is program revision)
Test Site	2	2
Test Temperature	25°C	25°C
Test Correlation Results	100%	100%
Number of Good Units Correlated @ ambient	510 pcs	510 pcs
500 units Bin 1 handler run (good units)	Passed	Passed
Number of Reject Units Correlated @ ambient	10 pcs	10 pcs
10 units Bin 1 datalog correlation (good units)	Passed	Passed
10 units rejects datalog correlation	Passed	Passed



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT 2 - PCN # : TB1602-01

Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
F1100NBGI	F1162NBGI	F1300NBGI	F1358NBGI
F1100NBGI8	F1162NBGI8	F1300NBGI8	F1358NBGI8
F1102NBGI	F1200NBGI	F1320NBGI	F1370NBGI
F1102NBGI8	F1200NBGI8	F1320NBGI8	F1370NBGI8
F1150NBGI	F1240NBGI	F1325NBGI	F1375NBGI
F1150NBGI8	F1240NBGI8	F1325NBGI8	F1375NBGI8
F1152NBGI	F1241NBGI	F1350NBGI	
F1152NBGI8	F1241NBGI8	F1350NBGI8	